## Low-pressure CVD and Plasma-Enhanced CVD

Ronald Curley, Thomas McCormack, and Matthew Phipps

- "Chemical Vapor Deposition"
- Thin films on substrate
- Chemical oven + insert gas = deposited film

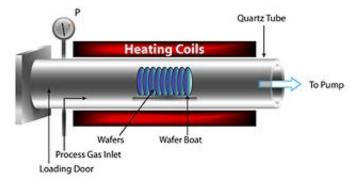
- Four steps<sup>[1]</sup>:
  - 1. Transport gas species to surface
  - 2. Gas species absorption into surface
  - 3. Reaction deposits products
  - 4. Remove unwanted products and leftover reactant

- Velocity ratio (molecules/s, not meters/s!):
  - Mass transport velocity
    - Depends on pressure
  - Surface reaction velocity
    - Does not depend on pressure
- Low ratio -> pure; well-controlled thickness
- High ratio -> contaminants; poorly-controlled thickness

- Atmospheric-pressure CVD (APCVD) velocity ratio too high: ~1:1
- Mass transport velocity proportional to 1/pressure<sup>[2]</sup>
- 1 atm ~= 100 kPa

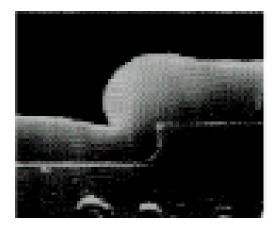
- LPCVD typical pressure: 10-1000 Pa
- Ratio 1:100–1:10,000!
- Reduced film variation
- Increased purity

- Substrate inserted
- Tube evacuated to 0.1 Pa
- Process gas ("working gas") added at 10-1000 Pa
- Reaction performed
- Substrate removed



Source: [3]

- Best for polysilicon, using SiH4
- Oxides, PSG as well
- Nitride encapsulation



Source: [4]

#### Advantages:

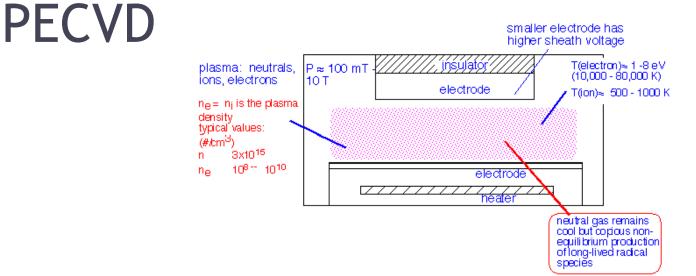
- Excellent uniformity of thickness & purity
- Simple
- Reliable/reproducible
- Homogenous layer

#### **Disadvantages:**

- Slows down deposition rate
- Requires high temperatures, <600°C</li>

## PECVD

- Plasma added with reactive gases
- RF voltage excites plasma
- Only electrons are hot, not ions: low temperatures possible



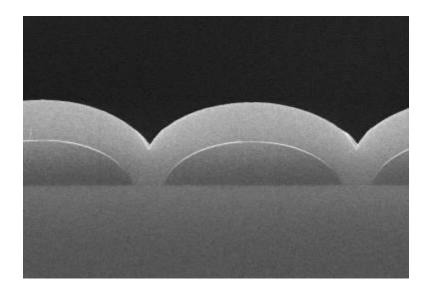
Picture: http://timedomaincvd.com/CVD\_Fundamentals/plasmas/capacitive\_plasma.html

Film	Reactive Gas	Thermal Deposition CVD (Celsius)	Plasma Enhanced CVD (Celsius)
Silicon Nitride	SIH4 or S1H2C12 & NH3	750	200-500
Silicon dioxide	SiH4 & O2	350-550	200-400
Amorphous silicon	SiH441	550-650	200-400

Table: http://www.eng.auburn.edu/~tzengy/ELEC7730/ELEC%207730%20Fall%202003/Fall%202003%20Presentation%201/Park%20-%20PECVD.ppt

## PECVD

### Conformal step coverage of PECVD $Si_xN_y$



http://www.hitech-projects.com/dts/docs/pecvd.htm

# PECVD

#### Advantages

- Low temperature
- Higher film density
- Higher dielectric constant
- Good step coverage
- Chamber easy to clean

#### Disadvantages

- Equipment is expensive
- Plasma bombardment is stressful
- Small batch sizes: 1-4 wafers, one side
- Compare to LPCVD: at least 25 wafers, both sides<sup>[5]</sup>



### References:

- [1] A Stoffel, A Kovács, W Kronast and B Müller, "LPCVD against PECVD for micromechanical applications" J. Micromech. Microeng., Vol. 6 No. 1 pp. 20-33, Mar. 1996
- [2] Ivanda, Mile, "Implementation and Development of the LPCVD Process", [Online], Available: http://www.irb.hr/en/str/zfm/labs/lmf/Previous\_projects/LPCVD/ [Accessed: 24 Nov. 2011]
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- [4] Doolittle, Alan, "Thin Film Deposition and Epitaxy", [Online], Available FTP: http://users.ece.gatech.edu/~alan/ECE6450/Lectures/ECE6450L13and14-CVD%20and%20Epitaxy.pdf [Accessed: 23 Nov. 2011]
- [5] MEMSnet, "MEMS Thin Film Deposition Processes", [Online], Available: http://www.memsnet.org/mems/processes/deposition.html [Accessed: 23 Nov. 2011]
- [6] "Plasma-Enhanced CVD." Hitech-Projects. 2011. 28 Nov. 2011 < http://www.hitech-projects.com/dts/docs/pecvd.htm>.
- [7] Mahalik, Nitaigour. <u>Introduction to Microelectromechanical Systems (MEMS)</u>. New Delhi, India. Tata McGraw-Hill, 2007.
- [8] "Plasma (Physics)." Wikipedia. 29 Nov. 2011. 29 Nov 2011. <a href="http://en.wikipedia.org/wiki/Plasma\_%28physics%29">http://en.wikipedia.org/wiki/Plasma\_%28physics%29</a>>.
- [9] "Fundamentals of Chemical Vapor Deposition Plasmas for CVD." <u>TimeDomain CVD, Inc</u>. 2002. 29 Nov. 2011.<<u>http://timedomaincvd.com/CVD\_Fundamentals/plasmas/plasma\_deposition.html</u>>.